

PART NUMBER

COMPONENT SPECIFICATION



Component Specification For Ceramic Hermetically Sealed, Radiation-Hard Transistor Optocouplers

Features	Applications			
 Radiation Tolerance tested up to 150 Krad(Si) 	Space Radiation Equipment			
■ High Isolation Voltage up to 1,500 V _{DC}	 Military and high reliability systems 			
 High Current Transfer Ratio 	Medical instruments			
 Hermetically Sealed 	 MOS/CMOS Applications 			
	Logic Interfacing			
	Data Transmission			
	■ Power Supply			
	■ Modems			

DESCRIPTION

The CSM166 is a hermetically sealed, dual or quad channel optically coupled isolator. Each channel is composed of a Gallium Arsenide infrared emitting diode and silicon phototransistor.

The series is being used in environments encountered by space applications. Package styles for this device include a 16-Pin flatpack package, with solder dip options available.

Absolute maximum ratings, recommended operating conditions, electrical specifications and performance characteristics are identical for all units. Any exceptions, due to packaging variations and limitations, are as noted.







aerospace sector certification scheme



ISOCOM Limited is AS9100 certified for the design and manufacture of electronic and optoelectronic components.

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STANDARDS

The following specifications have been complied with in the manufacturing of this product -

Aerospace Compliance Standards

AS9100D & ISO 9001:2015 - Design & Manufacture of Electronic and Optoelectronic Components (Ref GB15/92780)

Military Compliance Specifications

MIL-PRF-38534 - General Specification for Hybrid Microcircuits

MIL-PRF-19500 - General Specification for Discrete Semiconductor Devices

Military Compliance Standards

MIL-STD-202 - Test Method Standard Electronic and Electrical Component Parts

MIL-STD-883 - Test Method Standard Microcircuits

MIL-STD-750 - Test Method Standard for Semiconductor Devices

SCREENING INFORMATION

Our products can be screened to MIL-PRF-38534, applying test methods from MIL-STD-883; MIL-PRF-19500, applying test methods of MIL-STD-750; or a combination thereof. Please contact us for more information relating to the applicable screening processes.

AMENDMENT RECORD

Issue No.	Date	Description		
1	December 2013	First Issue.		
2	May 2018	Updated Standards Section.		
3	May 2018	Updated Standards Section. Removed Screening and Group Testing Information.		
4	September 2020	Updated Quality Management Logos. Removed IECQ Logos.		
5	January 2021	Removed Lot Definitions.		
6	May 2022	Added Radiation Testing and Electrical Testing diagrams, Updated Format, Added Render		
7	June 2022	Updated Electrical Characteristic Graphs and Added Screening Flow		
8	June 2023	Updated Marking Image		
9	August 2023	Added pin configuration, updated screening, updated circuit drawings, updated electrical characteristics		

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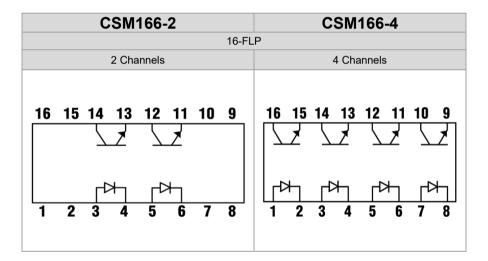
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PACKAGE STYLES AND CONFIGURATION OPTIONS

Package	16-	16-FLP			
Lead Style		-			
Channels	2	4			
Common Channel Wiring		-			
Isocom Part Number and Options					
Commercial	CSM166-2	CSM166-4			
Defense Screen Level	CSM166-2/L2	CSM166-4/L2			
Space Screen Level	CSM166-2/L2S	CSM166-4/L2S			
Standard Finish	Gold	l Plate			
Solder Dipped	Optio	Option #20			

FUNCTIONAL DIAGRAMS



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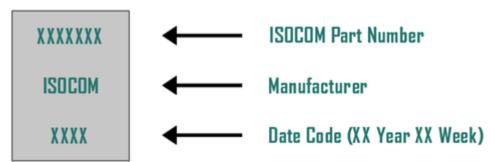
PIN OUT

	PIN NUMBER	FUNCTION
	1	NC
	2	NC
	3	Anode
	4	Cathode
	5	Anode
	6	Cathode
CSM166-2	7	NC
	8	NC
	9	NC
	10	NC
	11	Emitter
	12	Collector
	13	Emitter
	14	Collector
	15	NC
	16	NC

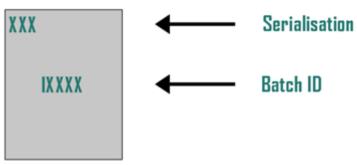
	PIN NUMBER	FUNCTION
	1	Anode
	2	Cathode
	3	Anode
	4	Cathode
	5	Anode
	6	Cathode
CSM166-4	7	Anode
	8	Cathode
	9	Emitter
	10	Collector
	11	Emitter
	12	Collector
	13	Emitter
	14	Collector
	15	Emitter
	16	Collector

DEVICE MARKING

FRONT OF DEVICE



BACK OF DEVICE



FOR SPACE SCREENED PARTS ONLY

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ABSOLUTE MAXIMUM RATINGS

T_A = 25°C U.O.S.

Storage Temperature	-65°C to +150°C					
Operating Temperature	-55°C to +125°C					
Lead Soldering Temperature	260°C 1.6mm	260°C 1.6mm from case for 10 seconds				
Input-to-Output Isolation Voltage	û1,500 V _{DC}	û1,500 V _{DC}				
Input Diode						
Forward DC Current	50mA					
Reverse DC Voltage	7V					
Peak forward Current	1.5A	≤ 10µs				
Power Dissipation	150mW					
Output Transistor						
Collector-Emitter Voltage	70V					
Emitter-Collector Voltage	7V					
Collector-Base Voltage	70V	≤ 10µs				
Collector Current	100mA	t =1ms				
Power Dissipation	150mW	Derate linearly above 100°C at 1.4W/°C				
Coupled Device						
Power Dissipation	360mW					
Soldering Temperature, Soldering Iron	260.5°C	This part shall not be re-soldered until 3 minutes have elapsed.				
Soldering Temperature, Vapour Phase	220.40°C	This part shall not be re-soldered until 3 minutes have elapsed.				
ESD Classification	Class 2	Class 2 with minimum critical path voltage of 4,000 to 15,999V. MIL-STD-883				



ELECTRICAL CHARACTERISTICS

 $T_A = -55^{\circ}C - 125^{\circ}C \text{ U.O.S.}$

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Input Diode Electric	cal Characte	ristics				
Forward Voltage	V _F	I _F = 10mA	0.7	1.2	1.8	V
Reverse Current	I _R	V _R = 3.0V	-	-	100	μA
Output Detector Ele	ectrical Char	acteristics	'			
Collector-Emitter Breakdown Voltage	V _{(BR)CEO}	I _C = 0.1mA	70	100	-	V
Collector-Base Breakdown Voltage	V _{(BR)CBO}	I _B = 100μA	70	200	-	V
Emitter-Collector Breakdown Voltage	V _{(BR)ECO}	I _E = 0.1mA	7	9	-	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	I _B = 1mA	5	-	-	V
Collector–Emitter Leakage Current	I _{CEO}	V _{CE} = 20V, I _F = 0A	-	7	100	μA
Coupled Electrical	Characterist	ics				
		$I_F = 1.0 \text{mA}, V_{CE} = 1 \text{V}$	200	-	-	%
	nsfer Ratio	$I_F = 3.0 \text{mA}, V_{CE} = 1 \text{V}$	200	-	-	%
DC Current Transfer Ratio		I _F = 15.0mA, V _{CE} = 1V	100	-	-	%
(Pre-Radiation)	I _{C/} I _F	I _F = 10.0mA, V _{CE} = 5V	350	-	-	%
		I _F = 15.0mA, V _{CE} = 5V	100	-	-	%
		I _F = 1.0mA, V _{CE} = 15V	300			%
Collector-Emitter Saturation Voltage	V _{CE(Sat)}	I _C = 10.0 mA I _F = 20 mA	-	-	0.22	V
Isolation Voltage (1)	V in-out	T = 5s	1,500	-	-	V_{DC}
Input to Output Resistance (1)	R in-out	V _{IO} = 500V	-	10 ¹¹		Ω
Rise Time	t _r	$R_L = 100\Omega$, $V_{CC} = 10V$, $I_F = 10mA$	-	6	12	μs
Fall Time	t _f	$R_L = 100\Omega$, $V_{CC} = 10V$, $I_F = 10mA$	-	6	12	μs
Propagation Delay – H-L	t _{PHL}	$R_L = 100\Omega$, $V_{CC} = 10V$, $I_F = 10mA$	-	-	5.0	μs
Propagation Delay – L-H	t _{PLH}	$R_L = 100\Omega$, $V_{CC} = 10V$, $I_F = 10mA$	-	-	5.0	μs
		$I_F = 1.0 \text{mA}, V_{CE} = 1 \text{V}$	200	-	-	%
		I _F = 3.0mA, V _{CE} = 1V	100	-	-	%
DC Current Transfer Ratio		I _F = 15.0mA, V _{CE} = 1V	66	-	-	%
(Post-Radiation)	I _{C/} I _F	I _F = 10.0mA, V _{CE} = 5V	160	-	-	%
		I _F = 15.0mA, V _{CE} = 5V	40	-	-	%
		I _F = 1.0mA, V _{CE} = 15V	250	-	-	%

Notes:

1. Measurements with inputs shorted together and outputs shorted together.

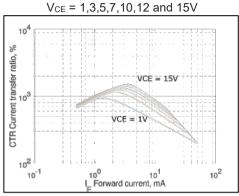
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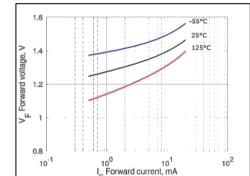
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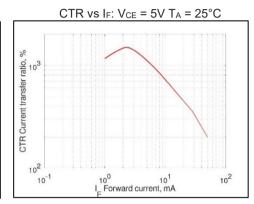
ELECTRICAL CHARACTERISTICS

Typical Graphs - Contact Office for more information

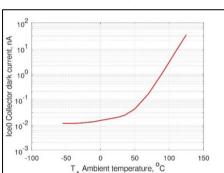


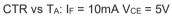


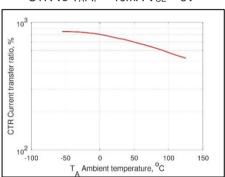
V_F V_S I_F

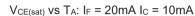


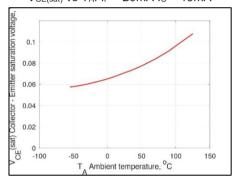




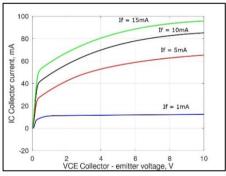








Ic vs Vce: TA = 25°C

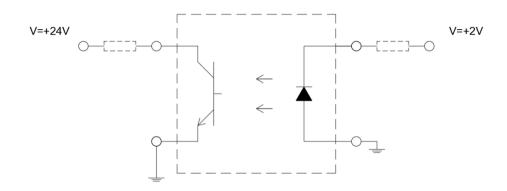


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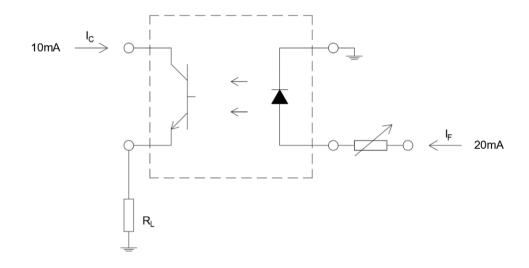
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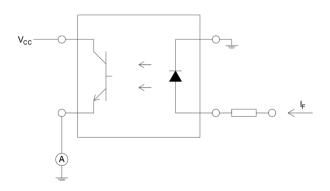
HTRB TEST CIRCUIT



ELECTRICAL CIRCUIT FOR BURN-IN AND OPERATING LIFE TESTS



ELECTRICAL MEASUREMENT OF COLLECTOR CURRENT

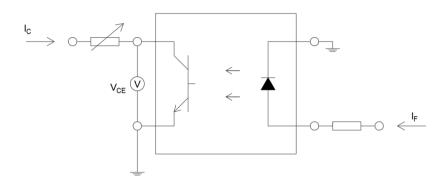


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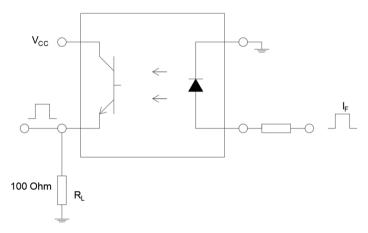
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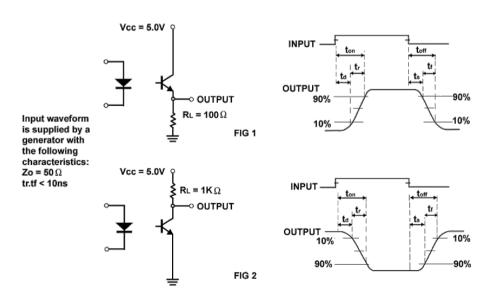
ELECTRICAL MEASUREMENT OF COLLECTOR EMITTER SATURATION VOLTAGE



ELECTRICAL MEASUREMENT OF A.C PARAMETERS



SWITCHING TIME

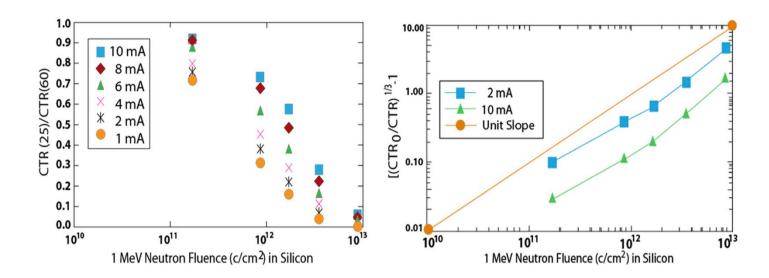


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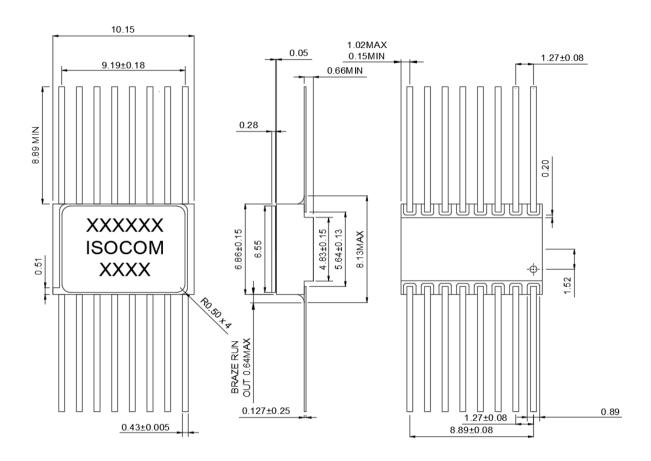
RADIATION TESTING





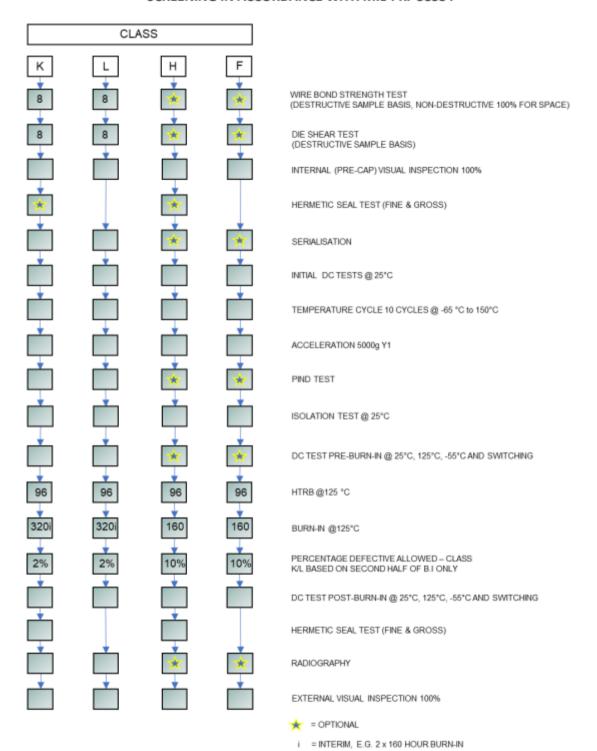
OUTLINE DRAWINGS

16-FLP





SCREENING IN ACCORDANCE WITH MIL-PRF 38534



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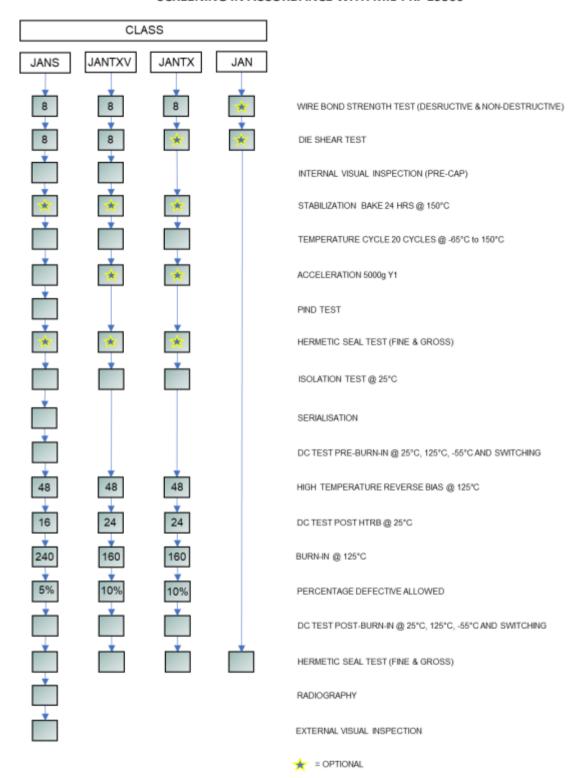


The following screening flow includes the electrical tests between each screening step, the referenced test method from MIL-STD 883 and the sample basis for Class K/L and H/F quality levels.

1 Wire bond strength (ND) (883) 2023 Optional 10 2 Wire bond strength (D) (883) 2011 Optional 8 de 3 Die Shear (883) 2019 Optional 8 de 4 Internal Visual (883) 2017 100% 10 5 Fine leak, Helium bomb, Leak detector (883) 1014, Con A1 Optional Optional Optional Optional Optional 10 6 Gross leak, Liquid bomb, -Bubble chamber (883) 1014, Con C1 Optional 10 7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	. (L28) 00% evices evices 00% tional tional 00% 00% 00%
2 Wire bond strength (D) (883) 2011 Optional 8 de 3 Die Shear (883) 2019 Optional 8 de 4 Internal Visual (883) 2017 100% 10 5 Fine leak, Helium bomb, Leak detector (883) 1014, Con A1 Optional Optional Optional Optional Optional Optional 10 6 Gross leak, Liquid bomb, -Bubble chamber (883) 1014, Con C1 Optional Optional 10 7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	evices evices 00% bional 00% 00% 00%
3 Die Shear (883) 2019 Optional 8 de 4 Internal Visual (883) 2017 100% 10 5 Fine leak, Hellum bomb, Leak detector (883) 1014, Con A1 Optional Optional Optional Optional Optional Optional 10 6 Gross leak, Liquid bomb, -Bubble chamber (883) 1014, Con C1 Optional Optional 10 7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	evices 00% bitional 00% 00% 00%
4 Internal Visual (883) 2017 100% 10 5 Fine leak, Helium bomb, Leak detector (883) 1014, Con A1 Optional Optional Optional Optional Optional Optional 10 7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	00% Microsol Microsol 00% 00% 00%
5 Fine leak, Helium bomb, Leak detector (883) 1014, Con A1 Optional 10 B Electrical Test 25°C 100% 10	otional official offi
6 Gross leak, Liquid bomb, -Bubble chamber (883) 1014, Con C1 Optional Optional 10 7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	oo% 00% 00% 00%
7 Serialisation of devices Optional 10 8 Electrical Test 25°C 100% 10	00% 00% 00%
8 Electrical Test 25°C 100% 10	00%
	00%
9 Temp cycle @ -65°C to 150°C (883) 1010, Con C, 10 cycles 100% 10	00%
10 Electrical Test 25°C 100% 10	NO.
11 Constant acceleration (883) 2001, 3000g, Y1 100% 10	JU 70
12 Electrical Test 25°C 109% 10	00%
13 P.I.N.D (883) 2020, Con A Optional 10	00%
14 Electrical Test 25°C 100% 10	00%
15 Isolation 100% @ 25°C (MIL-STD 202) 301 100% 10	00%
16 Electrical Test 25°C 100% 10	00%
17 Electrical Test 125°C Optional 10	00%
18 Electrical Test -55°C Optional 10	00%
19 Switching time 100% @ 25°C Optional 10	00%
20 HTRB @ 125°C - 96 hrs (883) 1015, con A 100% 10	00%
21 Electrical Test 25°C 100% 10	00%
	00% IO hrs
23 Electrical Test 25°C 100% 10	00%
24 Burn in @ 125°C (883) 1015, con B N/A 160	00% 0 hrs
25 Percentage defective allowable Pre/post Burn-in electrical and delta at 25°C only Max. 10% Max	x. 2%
26 Electrical Test 25°C Group A - 9G1 100% 10	00%
27 Electrical Test 125°C Group A - SG2 100% 10	00%
28 Electrical Test -55°C Group A - 9G3 100% 10	00%
29 Switching time 100% @ 25°C Group A - 9G9 100% 10	00%
30 Fine leak, Helium bomb, Leak detector (883) 1014, Con A1 100% 10	00%
31 Gross leak, Liquid bomb, -Bubble chamber (883) 1014, Con C1 100% 10	00%
32 Radiography (883) 2012 Optional 10	00%
33 External Visual (883) 2009 100% 10	00%



SCREENING IN ACCORDANCE WITH MIL-PRF 19500



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The following screening flow includes the electrical tests between each screening step, the referenced test method from MIL-STD 750 and the sample basis for Class JANTX, JANTXV and JANS quality levels.

Operation		NII 205 444A		Class	
No.	Operation	MIL-PRF 19500	JANTX (L2)	JANTXV (L2)	JANS (L2S)
1	Wire bond strength (ND)	(883) 2023	100%	100%	100%
2	Wire bond strength (D)	(750) 2037, Con D	4 devices	4 devices	8 devices
3	Die Shear	(750) 2017	4 devices	4 devices	8 devices
4	Internal Visual	(750) 2072	Optional	100%	100%
5	Stabilization Bake		Optional	Optional	Optional
6	Electrical Test @ 25°C		100%	100%	100%
7	Temp cycle (20 cycles @ -65°C to 150°C)	(750) 1051, Con F	100%	100%	100%
8	Electrical Test @ 25°C		100%	100%	100%
9	Constant acceleration	(750) 2006, 5000g, Y1	Optional	Optional	100%
10	Electrical Test @ 25°C		100%	100%	100%
11	P.I.N.D	(750) 2052, Con A	N/A	N/A	100%
12	Electrical Test @ 25°C		N/A	N/A	100%
13	Fine leak, Helium bomb, -Leak detector	(750) 1071 Con H1	Optional	Optional	Optional
14	Gross leak, Liquid bomb, Bubble chamber	(750) 1071, Con C	Optional	Optional	Optional
15	Serialisation of devices		N/A	N/A	100%
16	Isolation 100% @ 25°C	(MIL-STD 202) 301	100%	100%	100%
17	Electrical Test @ 25°C		100%	100%	100%
18	Electrical Test @ 125°C		100%	100%	100%
19	Electrical Test @ -55°C		100%	100%	100%
20	Switching time @ 25°C		100%	100%	100%
21	HTRB (125°C)	(750) 1039, Con A (80% VDS)	100% (48 hrs)	100% (48 hrs)	100% (48 hrs)
22	Electrical Test @ 25°C		100% (24 hrs)	100% (24 hrs)	100% (16 hrs)
23	Burn-In (125°C)	(750) 1039, Con B (80% VDS)	100% (160 hrs)	100% (160 hrs)	100% (240 hrs)
24	Percentage defective allowable	Pre/post Burn-in electrical and delta at 25°C only	100% @ 10% PDA	100% @ 10% PDA	100% @ 5% PDA
25	Electrical Test @ 25°C		100% (Group A, SG 2)	100% (Group A, SG 2)	100% (Group A, SG 2)
26	Electrical Test @ 125°C		100% (Group A, SG 3)	100% (Group A, SG 3)	100% (Group A, SG 3)
27	Electrical Test @ -55°C		100% (Group A, SG 3)	100% (Group A, SG 3)	100% (Group A, SG 3)
28	Switching time @ 25°C		100% (Group A, SG4)	100% (Group A, SG4)	100% (Group A, SG4)
29	Fine leak, Helium bomb, -Leak detector	(750) 1071 Con H1	100%	100%	100%
30	Gross leak, Liquid bomb, Bubble chamber	(750) 1071, Con C	100%	100%	100%
31	Radiography	(750) 2076	N/A	N/A	100%
32	External Visual	(750) 2071	N/A	N/A	100%

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MIL-PRF 19500 TYPICAL QCI TESTING PROCESS FLOW

Group	Sub Group Parameters				Quantity (accept number)		
Group	Group	Farameters	TM	JANS	JANTX, JANTXV		
	1	Visual and mechanical inspection	750-2071				
A (CI)	2	Static tests at +25°C	Datasheet	100%	100%		
A (CI)	3	Static tests at min and max. rated operating temp.	Datasheet	100%	100%		
	4	Dynamic test at +25°C	Datasheet				
		(JANS)		Large LOT (accept)	Small LOT (accept)		
	1	Physical dimension	750-2066	22 (0)	8 (0)		
	2	Solderability	750-2026	15 leads (0)	6 leads (0)		
		Temperature cycling (100 cycles)	750-1051				
		Hermetic seal (fine and gross leak)	750-1071	22 (0)	6 (0)		
		Electrical measurements	GRP-A- SG2	22 (0)	3 (0)		
B (PI)	3	Decap internal visual	750-2075	6 (0)	6 (0)		
B (FI)		Bond strength	750-2037	22 wires (0) or 11 (0)	12 wires (0) or 6 (0)		
		SEM	750-2077	11 (0)	6 (0)		
		Die shear	750-2017	11 (0)	6 (0)		
	4	Intermittent operation life (2000 cycles)	750-1037				
		Electrical measurements	GRP-A- SG2	22 (0)	12 (0)		
		(JANTXV, JANTX)		Large LOT (accept)	Small LOT (accept)		
	1	Solderability	750-2026	15 leads (0)	4 leads (0)		
		Temperature cycling (45 cycles incl. screening)	750-1051				
	2	Hermetic Seal (fine and gross leak)	750-1071	22 (0)	6 (0)		
	_	Electrical measurements	GRP-A-	(-)	- (-)		
			SG2				
B (PI)		Steady state op. life (340 Hrs) or	750-1026				
	3	intermittent op. life (2000 cycles)	or 750- 1037	45 (0)	12 (0)		
		Electrical measurements	GRP-A- SG2	10 (0)	(-)		
	4	Decap internal visual	750-2075	1 (0)	1 (0)		



MIL-PRF 19500 TYPICAL QCI TESTING PROCESS FLOW

Group	Sub Group	Parameters	ТМ	Sample plan	Small LOT (accept)		
	1	Physical dimensions (Not Req. JANS)	750-2066	15 (0)	6 (0)		
		Thermal shock (25 cycles, con B)	750-1056				
		Temperature cycling (45 cycles incl. screening)	750-1051		6 (0)		
C (PI)	2	Terminal strength	750-2036	22 (0)			
	2	Hermetic seal (fine and gross leak)	750-1071	22 (0)			
		Electrical measurements	GRP-A-				
		Electrical measurements	SG2				
		Constant acceleration (5000g, Y1 only)	750-2006	22 (0)	6 (0)		
	3	Electrical measurements	GRP-A-				
		Electrical measurements	SG2				
		Steady state op. life (1000 Hrs) or	750-1026				
		intermittent op. life (6000 cycles)	or 750-				
	6		1037	22 (0)	12 (0)		
		Electrical measurements	GRP-A-				
			SG2				
	7	Internal Gas Analysis - Moisture 10,000 ppmv limit	750-1018	3 (0)	3 (0)		



MIL-PRF 38534 TYPICAL QCI TESTING PROCESS FLOW

Group	Sub Group	b Group Parameters TM		Quantity (accept number)			
Gloup	Sub Group			К	н		
	1	Static tests at +25°C	Datasheet	100%	100%		
A (CI)	2	Static tests at max. rated operating temp.	Datasheet	100%	100%		
A (CI)	3	Static tests at min. rated operating temp.	Datasheet	100%	100%		
	9	Switching tests at +25°C	Datasheet	100%	100%		
	1	Physical dimension	883-2016	2 (0)	2 (0)		
	4	Internal visual and mechanical	883-2014	1 (0)	1 (0)		
B (PI)	5	Bond strength: Ultrasonic (on hotplate)	883-2011	2 (0)	2 (0)		
	6	Die shear strength	883-2019	2 (0)	2 (0)		
	7	Solderability	883-2003	1 (0)	1 (0)		
	8	Seal: a. Fine, b. Gross	883-1014	N/A	15 (0)		
		External visual	883-2009	5 (0)	5 (0)		
		Temperature Cycling	883-1010	5 (0)	5 (0)		
	1	Constant acceleration	883-2001	X	5 (0)		
		Seal (fine and gross)	883-1014	5 (0)	5 (0)		
		PIND	883-2020	5 (0)			
C (DI)		Visual examination	883-1010		5 (0)		
C (PI)				5 (0)	5 (0)		
		End-point electrical	GRP-A	5 (0)	5 (0)		
	2	Steady-state life test	883-1005	22 (0) or 5 (0)	22 (0) or 5 (0)		
		End-point electrical	GRP-A	22 (0) or 5 (0)	22 (0) or 5 (0)		
	3	Internal gas analysis	883-1018	3 (0) or 5 (1)	3 (0) or 5 (1)		
		Moisture 10,000 ppmv limit					
		Thermal shock	883-1011	5 (0)	5 (0)		
- 4		Stabilization bake	883-1008	5 (0)	5 (0)		
D (PI)	1	Lead integrity	883-2004	1 (0)	1 (0)		
		Seal: a. Fine, b. Gross	883-1014	5 (0)	5 (0)		

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Summary of key differences between MIL-PRF 19500 and MIL-PRF 38534 for space level testing:

	MIL-PRF 19500 - JANS	MIL-PRF 38534 – Class K
No. of Operation	31	33
(Screening) Steps	31	33
Optional		
Hermeticity	Occurs post P.I.N.D	Occurs post Internal Visual
Testing		
Temp cycle – No.	20	10
of Temp Cycles		
Acceleration -	5000g	3000g
Amount of g force		
HTRB – No. of	48	96
hours		
Burn-in – No. of	240 hrs in one successive burn-in	320 hrs (2 x 160 hrs with interim electrical)
hours		
PDA post burn-in	5% after 240 hrs burn-in	2% after second 160 hrs burn-in



DISCLAIMER

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ISOCOM Limited is AS9100 certified for the design and manufacture of electronic and optoelectronic components.

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